



FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEINFORMATION DISCLOSURE  
STATEMENT BY APPLICANT

(Use several sheets if necessary)

ATTY. DOCKET NO.  
I-2-81.2USSERIAL NO.  
09/880,977APPLICANT  
John W. HaimFILING DATE  
June 14, 2001GROUP  
266b

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>P.D.</i>	AA*	4	8	1	1	4	2	1	03/89	Havel et al.	—	—	
↑	AB*	5	0	2	2	0	4	9	06/91	Abrahamson et al.	↑	↑	
	AC*	5	0	5	6	1	0	9	10/91	Gilhausen et al.			
	AD*	5	1	1	3	5	2	5	05/92	Andoh			
	AE*	5	1	5	9	2	8	3	10/92	Jensen			
	AF*	5	2	3	5	6	1	4	08/93	Bruckert et al.			
	AG*	5	2	5	7	2	8	3	10/93	Gilhausen et al.			
	AH*	5	2	6	5	1	1	9	11/93	Gilhausen et al.			
	AI*	5	2	6	7	2	6	2	11/93	Wheatley, III			
	AJ*	5	2	9	7	1	6	2	03/94	Lee et al.			
	AK*	5	3	0	9	4	7	4	05/94	Gilhausen et al.			
	AL*	5	3	2	7	4	5	5	07/94	De Gaudenzi et al.			
↓	AM*	5	3	5	3	3	0	2	10/94	Bi	↓	↓	
<i>T.D.</i>	AN*	5	3	5	3	3	5	2	10/94	Dent et al.	↓	—	

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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
													YES	NO

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER

*DANIEL 2001*

DATE CONSIDERED

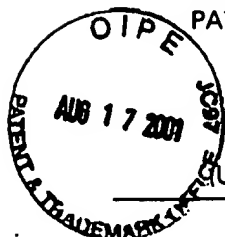
*4/11/01*

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## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>T.D.</i>	AO*	5	3	6	3	3	7	7	11/94	Sharpe	—	—	
<i>↑</i>	AP*	5	3	7	7	1	8	3	12/94	Dent	<i>↑</i>	<i>↑</i>	
	AQ*	5	4	0	6	5	5	9	04/95	Edem et al.			
	AR*	5	4	1	4	7	2	8	05/95	Zehavi			
	AS*	5	4	3	0	7	6	0	07/95	Dent			
	AT*	5	4	4	2	6	6	2	08/95	Fukasawa et al.			
	AU*	5	4	4	6	7	5	6	08/95	Mallinckrodt			
	AV*	5	6	1	9	5	2	4	04/97	Ling et al.			
<i>↓</i>	AW*	5	7	4	5	4	8	4	04/98	Scott	<i>↓</i>	<i>↓</i>	
<i>T.D.</i>	AX*	5	9	4	0	3	8	2	08/99	Haim	—	—	

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													YES	NO
<i>T.D.</i>	AY*	0	5	6	5	5	0	7	10/93	Europe	—	—		

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>T.D.</i>	BZ*	Patent Abstracts of Japan, Vol. 015, No. 003 (E-1019), 7 January 1991 & JP 02 256331 A (Sharp Corp.), 17 October 1990, see abstract.

EXAMINER

*DAIVL, DAN*

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*4/11/05*

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